Am27LS18 • Am27LS19 Low-Power Schottky 256-Bit Generic Series Bipolar PROM

DISTINCTIVE CHARACTERISTICS

- High Speed 55ns max commercial range access time
- Excellent performance over full MIL and commercial ranges
- Highly reliable, ultra-fast programming Platinum-Silicide fuses
- High programming yield
- · Low current PNP inputs
- High current open collector and three-state outputs
- · Fast chip select
- Access time tested with N² patterns
- Pin for pin replacements for industry standard products
- Common Generic PROM series electrical characteristics and simple programming procedures.

FUNCTIONAL DESCRIPTION

The Am27LS18 and Am27LS19 are high speed electrically programmable Schottky read only memories. Organized in the industry standard 32 x 8 configuration, they are available in both open collector Am27LS18 and three-state Am27LS19 output versions. After programming, stored information is read on outputs $O_0\text{-}O_7$ by applying unique binary addresses to $A_0\text{-}A_4$ and holding chip select input, $\overline{\text{CS}}$, at a logic LOW. If either chip select input goes to a logic HIGH, $O_0\text{-}O_7$ go to the OFF or high impedance state.

GENERIC SERIES CHARACTERISTICS

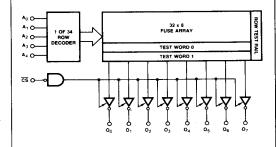
The Am27LS18 and Am27LS19 are members of an Advanced PROM series incorporating common electrical characteristics and programming procedures. All parts in this series are produced with a fusible link at each memory location storing a logic LOW and can be selectively programmed to a logic HIGH by applying appropriate voltages to the circuit.

All parts are fabricated with AMD's fast programming highly reliable Platinum-Silicide Fuse technology. Utilizing easily implemented programming (and common programming personality card sets) these products can be rapidly programmed to any customized pattern. Extra test words are pre-programmed during manufacturing to insure extremely high field programming yields and produce excellent parametric correlation.

Platinum-Silicide was selected as the fuse link material to achieve a well controlled melt rate resulting in large non-conductive gaps that ensure very stable long term reliability. Extensive operating testing has proven that this low-field, large-gap technology offers the best reliability for fusible link PROMs.

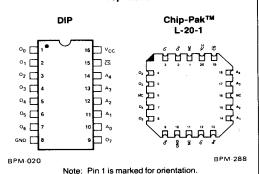
Common design features include active loading of all critical AC paths regulated by a built-in temperature and voltage compensated bias network to provide excellent parametric performance over MIL supply and temperature ranges. Selective feedback techniques have been employed to minimize delays through all critical paths producing the fastest speeds possible from Schottky processed PROMs.

BLOCK DIAGRAM



BPM-018

CONNECTION DIAGRAMS Top Views



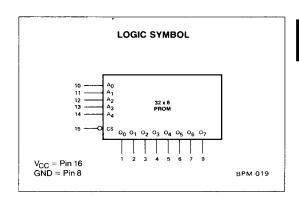
Chip-Pak is a trademark of Advanced Micro Devices, Inc.

MAXIMUM RATINGS (Above which the useful life may be impaired)

Storage Temperature	−65 to +150°C
Ambient Temperature with Power Applied	−55 to +125°C
Supply Voltage to Ground Potential (Pin 16 to Pin 8) Continuous	-0.5 to +7.0V
DC Voltage Applied to Outputs (Except During Programming)	-0.5V to +V _{CC} max
DC Voltage Applied to Outputs During Programming	21V
Output Current into Outputs During Programming (Max Duration of 1 sec)	250mA
DC Input Voltage	-0.5 to +5.5V
DC Input Current	-30 to +5mA

OPERATING RANGE

Range	Vcc	Temperature
COM'L	4.75 to 5.25V	$T_A = 0 \text{ to } +75^{\circ}\text{C}$
MIL	4.5 to 5.5V	$T_C = -55 \text{ to } + 125^{\circ}\text{C}$



ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE (Unless Otherwise Noted)

						Тур		
Parameters	Description	Т	est Conditions	5	Min	(Note 1)	Max	Units
V _{OH} (Am27LS19 only)	Output HIGH Voltage	V _{CC} = MIN, I _C V _{IN} = V _{IH} or V			2.4			Volts
V _{OL}	Output LOW Voltage	V _{CC} = MIN, I _C V _{IN} = V _{IH} or V					0.45	Volts
V _{IH}	Input HiGH Level		nput logical HIGH inputs (Note 2)		2.0			Volts
V _{IL}	Input LOW Level	Guaranteed in voltage for all				0.8	Volts	
l _{IL}	Input LOW Current	V _{CC} = MAX,		-0.010	-0.250	mA		
I IH	Input HIGH Current	V _{CC} = MAX,				25	μΑ	
I _{SC} (Am27LS19 only)	Output Short Circuit Current	V _{CC} = MAX,	te 3)	- 20	-40	- 90	mA	
lcc	Power Supply Current	All inputs = G V _{CC} = MAX	ND			60	80	mA
VI	Input Clamp Voltage	V _{CC} = MIN, I _{II}	N = -18mA				-1.2	Volts
				$V_{O} = 4.5V$			40	
I _{CEX}		$V_{CC} = MAX$ $V_{CS} = 2.4V$ Am27LS19 Vo		V _O = 2.4V			40	μΑ
		1.05 - 2.44	Only	$V_0 = 0.4V$			-40	
C _{IN}	Input Capacitance	V _{IN} = 2.0V @	f = 1MHz (Note 4	l)		4		
C _{OUT}	Output Capacitance	V _{OUT} = 2.0V	V _{OUT} = 2.0V @ f = 1MHz (Note 4)					pF

Notes: 1. Typical limits are at $V_{CC} = 5.0V$ and $T_A = 25^{\circ}C$.

- 3. Not more than one output should be shorted at a time. Duration of the short circuit should not be more than one second.
- 4. These parameters are not 100% tested, but are periodically sampled.

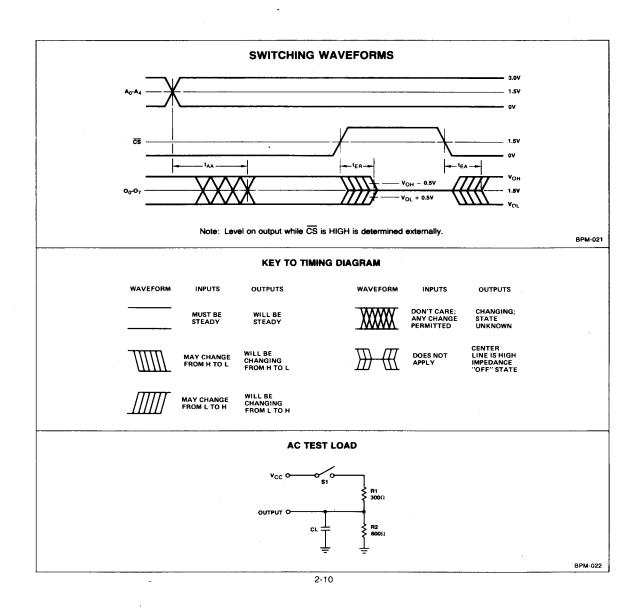
These are absolute voltages with respect to device ground pin and include all overshoots due to system and/or tester noise. Do not attempt to test these values without suitable equipment.

Am27LS18/LS19 SWITCHING CHARACTERISTICS OVER OPERATING RANGE

			Тур	. Ma		
Parameter	Description	Test Conditions	5V 25°C	COM'L	MIL	Units
t _{AA}	Address Access Time		30	55	75	ns
t _{EA}	Enable Access Time	AC Test Load (See Notes 1-3)	22	40	50	ns
t _{ER}	Enable Recovery Time	(222.121.00 + 0)	18	35	40	ns

Notes: 1. t_{AA} is tested with switch S_1 closed and $C_L = 30pF$.

 For open collector outputs, t_{EA} and t_{ER} are tested with S₁ closed to the 1.5V output level. C_L = 30pF.
 For three state outputs, t_{EA} is tested with C_L = 30pF to the 1.5V level; S₁ is open for high impedance to HIGH tests and closed for high impedance to LOW tests. t_{ER} is tested with C_L = 5pF. HIGH to high impedance tests are made with S₁ open to an output voltage of V_{OH} - 0.5V; LOW to high impedance tests are made with S₁ closed to the V_{OL} + 0.5V level.



PROGRAMMING

The Am27LS18 and Am27LS19 are manufactured with a conductive memory with the link in place is LOW. To program the device, the fusible links are selectively opened.

The fusible links are opened one at a time by passing current through them from a 20 volt supply which is applied to one memory output after the $\overline{\text{CS}}$ input is at a logic HIGH. Current is gated through the addressed fuse by raising the $\overline{\text{CS}}$ input from a logic HIGH to 15 volts. After 50 μ sec, the 20 volt supply is removed, the chip enabled, and the output level sensed to determine if the link has opened. Most links will open within 50 μ sec. Occasionally a link will be stronger and require additional programming cycles. The recommended duration of additional programming periods is 5 msec. If a link has not opened after a total elapsed programming time of 400 msec, further programming of the device should not be attempted. Successive links are programmed in the same manner until all desired bit locations have been programmed to the HIGH level.

Typical current into an output during programming will be approximately 140mA until the fuse link is opened, after which

the current drops to approximately 40mA. Current into the CS pin when it is raised to 15 volta is typically 1.5mA.

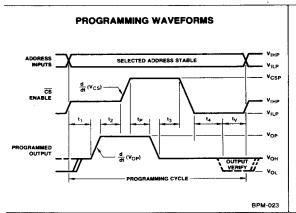
The memories may become hot during programming due to the large currents being passed. Programming cycles should not be applied to one device more than 5 seconds to avoid heat damage. If this programming time is exceeded, all power to the chip including V_{CC} should be removed for a period of 5 seconds after which programming may be resumed.

When all programming has been completed, the data content of the memory should be verified by sequentially reading all words. Occasionally this verification will show that an extra undesired link has been fused. Should this occur, immediately check the programming equipment to make sure that all device pins are firmly contacting the programming socket, that the input signal levels exhibit sufficient noise margins, and that the programming voltages are within the specified limits. All of these conditions must be maintained during programming. AMD PROMs are thoroughly tested to minimize unwanted fusing; fusing extra bits is generally related to programming equipment problems.

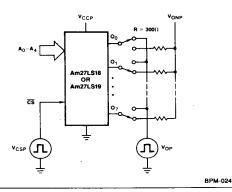
PROGRAMMING PARAMETERS

arameter Description		Min	Max	Units	
VCCP	V _{CC} During Programming	5.0	5.5	Volts	
ViHP	Input HIGH Level During Programming	2.4	5.5	Volts	
VILP	Input LOW Level During Programming	0.0	0.45	Volts	
V _{CSP}	CS Voltage During Programming	14.5	15.5	Voits	
V _{OP}	Output Voltage During Programming	19.5	20.5	Volts	
VONP	Voltage on Outputs Not to be Programmed	0	V _{CCP} +0.3	Volts	
IONP	Current into Outputs Not to be Programmed		20	mA	
d(V _{OP})/dt	Rate of Output Voltage Change	20	250	V/μsec	
d(V _{CS})/dt	Rate of CS Voltage Change	100	1000	V/µsec	
	Programming Period - First Attempt	50	100	μsec	
t _P	Programming Period - Subsequent Attempts	5.0	15	msec	

- Notes: 1. All delays between edges are specified from completion of the first edge to beginning of the second edge; i.e., not to the midpoints.
 - Delays t₁, t₂, t₃ and t₄ must be greater than 100 ns; maximum delays of 1 μsec are recommended to minimize heating during programming.
 - During t_v, a user defined period, the output being programmed is switched to the load R and read to determine if additional pulses are required.
 - 4. Outputs not being programmed are connected to VONP through resistor R which provides output current limiting.



SIMPLIFIED PROGRAMMING DIAGRAM



2-11

PROGRAMMING EQUIPMENT

Generic programming boards and device adapters are available from the sources listed below. In each case, the programming boards are used in these manufacturer's automatic

programmers to program all AMD generic series bipolar rnows; individual adapters are required for each pasic part type in the series.

SOURCE AND LOCATION

Data I/O Corp. P.O. Box 308 Issaquah, Wash. 98027 les. Pro-Log Corp. 2411 Garden Road

PROGRAMMER MODEL(S)

Model 5, 7 and 9

Monterey, Ca. 93940 M900 and M920

AMD GENERIC BIPOLAR

909-1286-1

M900 and I PM9058

PROM PERSONALITY BOARD Am27LS18 • Am27LS19 ADAPTERS AND CONFIGURATORS

PA16-6 and 32 x 8 (L)

OBTAINING PROGRAMMED UNITS

Programmed devices may be purchased from your distributor or Advanced Micro Devices. The program data should be submitted in the form of a punched paper tape and must be accompanied by a written truth table. The punched tape can be delivered with your order or may be transmitted over a TWX machine or time-sharing terminal. ASCII BPNF is our preferred paper tape format.

Truth tables are also acceptable, but are much less desirable especially for larger density PROMs. Submission of a truth table requires the generation of a punched paper tape at the distributor or factory resulting in longer lead times, greater possibility of error, and higher cost.

ASCII BPNF

An example of an ASCII tape in the BPNF format is shown below. They can be punched on any Teletype® or on a TWX or Telex machine. The format chosen provides relatively good error detection. Paper tapes must consist of:

- 1. A leader of at least 25 rubouts.
- The data patterns for all 32 words, starting with word 0, in the following format:
 - a. Any characters, including carriage return and line feed, except "B".
 - The letter "B", indicating the beginning of the data word.
 - c. A sequence of eight Ps or Ns, starting with output O7.
 - d. The letter "F", indicating the finish of the data word.
 - e. Any text, including carriage return and line feed, except the letter "B".

3. A trailer of at least 25 rubouts.

A P is a HIGH logic level = 2.4 volts. An N is a LOW logic level = 0.4 volts.

A convenient pattern to use for the data words is to prefix the word (or every few words with the word number, then type the data word, then a comment, then carriage return and line feed as shown below. There must be no characters between the B and the F except for the eight Ps and Ns. If an error is made in a word, the entire word must be cancelled with rubouts back to the letter B, then the word re-typed beginning with the B.

When TWXing your tape, be sure the tape is in even parity. Parity is not necessary if the tape is mailed.

TYPICAL PAPER TAPE FORMAT

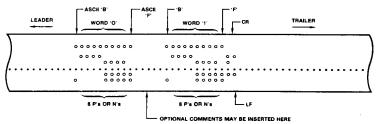
øøø	BPNPPNNNPF	WORD ZERO (R) (L)
	BPPPPPPNNF	COMMENT FIELD (R) (L)
øø2	BNNNPPPPNF	ANY (R) (L)
	BNNNNNNNF	TEXT (R) (L)
ØØ4	BPNNNNNNPF	CAN (R) (L)
	BNPPNPPNNF	GO (R) (L)
øø6	BPNNPPPNNF	HERE (R) (L)
	::::::::::	:
Ø31	BNNNNPPPNF	end (R) (L)
(R) = (CARRIAGE RETU	RN
(L)= L	INE FEED	

RESULTING DEVICE TRUTH TABLE (CS = LOW)

A4	A_3	A_2	Αt	A ₀	0,	06	05	04	03	02	01	00
L	Ł	L.	L	L	н	L	н	н	L	L	L	н
L,	L	L	L	н.	н	н	н	н	н	н	L	L
L	L	L	н	L	Ł	L	L	н	н	н	н	L
L	L	L	н	Н	L	Ł	L	L	L	L	L	L
L	L	H	L	L	н	L	L	L	L	L	L	н
L	L	н	L	н	L	н	н	l.	н	н	L	L
L	L :	н	н	L	н	L	L	H	н	н	L	L
н	н :	н	н	н	L	L	Ł	Ĺ	н	н	н	L

BPM-025

ASCII PAPER TAPE

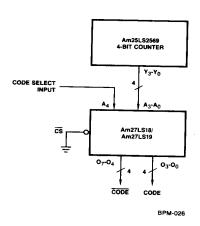


APPLYING THE Am27LS18 AND Am27LS19

The Am27LS18 and Am27LS19 PROMs may be used as code converters. Examples include conversion of hexadecimal, octal or BCD to seven segment display drive format. In many code conversion applications an extra PROM address input is available and may be used as a polarity control, blanking con-

trol or code selector input. The use of a single Am27LS18 or Am27LS19 to convert the outputs of a binary counter to either excess three or gray code format is illustrated below. In this case both codes are generated in true and complemented form simultaneously.

TRUTH TABLE



		AD	DR	ESS	3		CO	MF	LEI	MEN	Т		T	RUE		T
	A ₄	A ₃	A ₂	A ₁	A ₀		0,	0	, O,	04		О3		2 0.		
	0	0	0	0	0	T	1	1	0	0	7	0	0	1	1	
	0	0	0	0	1	1	1	0	1	1		ŏ	1	ò	ò	ĺ
	0	0	0	1	0	ı	1	0	1	Ó	i	ō	1	ō	1	
	0	0	0	1	1	ĺ	1	0	0	1	ļ	ō	1	1	ó	@
	0	0	1	0	0		1	0	0	0	- 1	0	1	1	1	ା ନ
	0	0	1	0	1		0	1	1	1	1	1	0	0	Ó	D.
i	0	0	1	1	0	1	0	1	1	0		1	0	0	1	Š
	0	0	1	1	1		0	1	0	1	1	1	0	1	0	EXCESS THREE
	0	1	0	0	0	İ	0	1	0	0	-	1	0	1	1	🕏
i	0	1	0	0	1	-	0	0	1	1	ı	1	1	0	0	i m
1	0	1	0	1	0	1	Х	Х	Х	Х		Х	Х	Х	Х	
1	0	1	0	1	1	[Х	Х	X	Х	1	Х	Х	Х	Х	CODE
ł	0	1	1	0	0	l	Х	Х	Х	Х	İ	X	Х	Х	Х	m
Į	0	1	1	0	1	ĺ	X	Х	Х	Х		Х	Х	X	Х	
1	0	1	1	1	0		X	Х	Х	X	-	Х	Х	Х	Х	1
1	0	1	1	1	1	ļ	X	Х	Х	X		Х	Х	Х	Х	1
-	1	0	0	0	0	ĺ	1	1	1	1		0	0	0	0	
ĺ	1	0	0	0	1		1	1	1	0		0	0	0	1	
1	1	0	0	1	0		1	1	0	0	1	0	0	1	1	
	1	0	1	0			1	1	0	1	l	0	0	1	0	
l	1	0	1	0	0		1	0	0	1		0	1	1	0	-
	i	0	1	1	0		1	0	0	0	Ĺ	0	1	1	1	ြ ၈
١	i	Ö	1	1	1		1	0	1	0		0	1	0	1	GRAY CODE
1	i	1	ò	ó	6		0	0	1	1	İ	0	1	0	0	7
	i	1	0	0	1		0	0	1	1		1	1	0	0	Ω
l	i	i	ō	1	0		0	0	0	0		1	1	0	1	
ĺ	i	i	ō	1	1		0	0	0	0		1	1	1	1	m
-	1	i	1	ò	6		0	1	0	1		1	1	1	0	l
	1	1	1	0	1		0	1	0	0		1	0	1	0	١ ،
ĺ	1	i	i	1	6		0	1	1	-		1	0	1	1	
-	i	i	1	1	1		0	i	1	0		1	0	0	1 .	
L,		<u> </u>		<u> </u>				<u>. </u>			L		U	0	0	

PROM PROGRAMMING EQUIPMENT INFORMATION

The PROM Programming Equipment from the following manufacturers has been evaluated and approved by AMD:

Source and Location	Data I/O 10525 Willows Rd. N.E. Redmond, WA 98052	Pro-Log Corporation 2411 Garden Road Monterey, CA 93940	International Microsystems, Inc. 11554 C. Avenue Auburn, CA 95603	Kontron Electronic, Inc. 630 Price Avenue Redwood City, CA 94063	Digelec, Inc. 7335 E. Acon Scottsdale, A		Stag Systems, Inc. 528-5 Weddell Dr. Sunnyvale, CA 94086	
Programmer Model(s)	Model 5, 7, and 9 Systems 17, 19, 29 and 100	M900, M900B, M910, M920, and M980	IM1010	MPP-80	UPP-801	UPP-803	PPX	
AMD Generic Bipolar PROM Personality Module	MD Generic 909-1286-1 Rev H* PM 919-1286-1 Rev H* Unipak Rev H*		IM AMDGEN1	MOD 14	PM 102	FAM-12	PM 2000 Code 90	
Am27LS18/19	715-1407-1	PA 16-6 and 32 x 8(L)	IM 32 x 8-16-AMD	SA 3-1 B 32 x 8/16	DIS-156 AM	DA-22	AM110	

^{*}Rev shown is minimum approved revision.

OBTAINING PROGRAMMED UNITS

Programmed devices may be purchased from your distributor or Advanced Micro Devices. The program data should be submitted in the form of a punched paper tape and must be accompanied by a written truth table. The punched tape can be delivered with your order or may be transmitted over a TWX machine or a time-sharing terminal. ASCII BPNF is our preferred paper tape format.

Truth tables are also acceptable, but are much less desirable especially for larger density PROMs. Submission of a truth table requires the generation of a punched paper tape at the distributor or factory resulting in longer lead times, greater possibility of error and higher cost.

ORDERING INFORMATION

Speed Selection	Orde	r Code	Bookses			
	Open Collector	Three-State	Package - Type (Note 1)	Screening Flow Code (Note 2)	Operating Range (Note 3)	
55ns	AM27LS18PC AM27LS18PCB AM27LS18DC AM27LS18DCB AM27LS18LC AM27LS18LC	AM27LS19PC AM27LS19PCB AM27LS19DC AM27LS19DCB AM27LS19LC AM27LS19LCB	P-16-1 P-16-1 D-16-1 D-16-1 L-20-1 L-20-1	C-1 B-1 C-1 B-1 C-1 B-1	COM'L	
75ns	AM27LS18DM AM27LS18DMB AM27LS18FM AM27LS18FMB AM27LS18LM AM27LS18LMB	AM27LS19DM AM27LS19DMB AM27LS19FM AM27LS19FMB AM27LS19LM AM27LS19LMB	D-16-1 D-16-1 F-16-1 F-16-1 L-20-1 L-20-1	C-3 B-3 C-3 B-3 C-3 B-3	MIL	

Notes: 1. P = Molded DIP, D = Hermetic DIP, L = Chip-Pak, F = Cerpak. Number following letter is number of leads.

This device is also available in die form selected to commercial and military specifications. Pad layout and bonding diagram available upon request.

Levels C-1 and C-3 conform to MIL-STD-883, Class C. Levels B-1 and B-3 conform to MIL-STD-883, Class B.

^{3.} See Operating Range Table.